

States in the international economy, the international reputation of the United States as a supplier of goods and technology; and

6. The ability of the United States to effectively enforce the controls.

BIS is particularly interested in receiving comments on the economic impact of proliferation controls. BIS is also interested in industry information relating to the following:

1. Information on the effect of foreign policy-based export controls on sales of U.S. products to third countries (*i.e.*, those countries not targeted by sanctions), including the views of foreign purchasers or prospective customers regarding U.S. foreign policy-based export controls.

2. Information on controls maintained by U.S. trade partners. For example, to what extent do U.S. trade partners have similar controls on goods and technology on a worldwide basis or to specific destinations?

3. Information on licensing policies or practices by our foreign trade partners that are similar to U.S. foreign policy based export controls, including license review criteria, use of conditions, and requirements for pre- and post-shipment verifications (preferably supported by examples of approvals, denials and foreign regulations).

4. Suggestions for bringing foreign policy-based export controls more into line with multilateral practice.

5. Comments or suggestions to make multilateral controls more effective.

6. Information that illustrates the effect of foreign policy-based export controls on trade or acquisitions by intended targets of the controls.

7. Data or other information on the effect of foreign policy-based export controls on overall trade at the level of individual industrial sectors.

8. Suggestions for measuring the effect of foreign policy-based export controls on trade.

9. Information on the use of foreign policy-based export controls on targeted countries, entities, or individuals. BIS is also interested in comments relating generally to the extension or revision of existing foreign policy-based export controls.

Parties submitting comments are asked to be as specific as possible. All comments received before the close of the comment period will be considered by BIS in reviewing the controls and in developing the report to Congress. All comments received in response to this notice will be displayed on BIS's Freedom of Information Act (FOIA) Web site at <http://www.bis.doc.gov/foia> and on the Federal e-Rulemaking portal at www.Regulations.gov. All comments

will also be included in a report to Congress, as required by section 6 of the EAA, which directs that BIS report to Congress the results of its consultations with industry on the effects of foreign policy-based controls.

Dated: August 27, 2012.

Kevin J. Wolf,

Assistant Secretary for Export Administration.

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DEPARTMENT OF COMMERCE

International Trade Administration

Application(s) for Duty-Free Entry of Scientific Instruments

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be postmarked on or before September 27, 2012. Address written comments to Statutory Import Programs Staff, Room 3720, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5:00 p.m. at the U.S. Department of Commerce in Room 3720.

Docket Number: 12-034. **Applicant:** Stony Brook University, 100 Nicolls Rd., Stony Brook, NY 11794. **Instrument:** Electron Microscope. **Manufacturer:** JEOL Ltd., Japan. **Intended Use:** The instrument will be used to study the morphology and crystalline structure of metallic, semi-conductor, or polymeric materials. **Justification for Duty-Free Entry:** There are no instruments of the same general category manufactured in the United States. **Application accepted by Commissioner of Customs:** July 11, 2012.

Docket Number: 12-035. **Applicant:** The City College of New York, Office of the Dean of Science, Marshak 1320, 160 Convent Ave., New York, NY 10031. **Instrument:** Electron Microscope. **Manufacturer:** JEOL Ltd., Japan. **Intended Use:** The instrument will be used for several projects including the examination of the distribution of intracellular proteins that mediate the ligand-mediated chemotaxis of cells within a micro-controlled environment, the study of nanoparticles, and the

structure of influenza vaccine strains. **Justification for Duty-Free Entry:** There are no instruments of the same general category manufactured in the United States. **Application accepted by Commissioner of Customs:** July 30, 2012.

Dated: August 30, 2012.

Callie H. Conroy,

Acting Director of Subsidies Enforcement, Import Administration.

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DEPARTMENT OF COMMERCE

International Trade Administration

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